

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Spirox Corporation/National Tsing Hua University

Title: DIAGONAL TESTING METHOD
FOR FLASH MEMORIES

Express Mail No. EV 126287357US

Serial No.: Not assigned

Date of Mailing: June 24, 2003

Filing Date: June 24, 2003

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Mail Stop: Patent Application

Sir:

Applicant assignee's undersigned attorneys, who prepared the above-identified application, are aware of the references listed on the attached Form PTO-1449, copies of which are enclosed herewith, and which are relevant to said application.

Respectfully submitted,

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By


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FORM PT0-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

404800

SERIAL NO.

Not assigned

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Spirox Corporation

FILING DATE

June 24, 2003

GROUP

Not assigned

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AM							
	AN							
	AO							
	AP							
	AQ							

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

AR	Yeh et. al, "Flash Memory Built-In Self Test Using March-Like Algorithms"
AS	Mohammad et al., "Testing Flash Memories", (pgs. 406-411), January 2000
AT	Mohammad et al., "Flash Memory Disturbances: Modeling and Test" (pgs. 1- 9)

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your next communication to applicant.